

<b>Notice of References Cited</b>	Application/Control No. <div style="text-align: center;">09/886,511</div>		Applicant(s)/Patent Under Reexam <div style="text-align: center;">Coates et al.</div>	
	Examiner <div style="text-align: center;">Rodney McDonald</div>		Art Unit <div style="text-align: center;">1753</div>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>	
A	6,217,722	4/2001	Jankowski et al.	204	192.21
B	5,367,285	11/1994	Swinehart et al.	338	308
C	4,591,417	5/1986	Kaiser et al.	204	192.23
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L					
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**FOREIGN PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Country	Name	Classification <sup>2</sup>	
N						
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Hohenstein, "Cermet Resistors by Concurrent rf and dc Sputtering", Communications, October 1967, pp.65-66.
V	
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X	

\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a). <sup>1</sup> Dates in MM-YYYY format are publication dates. <sup>2</sup> Classifications may be U.S. or foreign.